NEC

MOS INTEGRATED CIRCUIT

μPD42S17405L, 4217405L

3.3 V OPERATION 16 M-BIT DYNAMIC RAM 4 M-WORD BY 4-BIT, EDO

Description

The μPD42S17405L, 4217405L are 4,194,304 words by 4 bits CMOS dynamic RAMs with optional EDO.
EDO is a kind of the page mode and is useful for the read operation.
Besides, the μPD42S17405L can execute $\overline{CAS}$ before $\overline{RAS}$ self refresh.
The μPD42S17405L, 4217405L are packaged in 26-pin plastic TSOP (II) and 26-pin plastic SOJ.

Features

- EDO (Hyper page mode)
- 4,194,304 words by 4 bits organization
- Single +3.3 V ±0.3 V power supply
- Fast access and cycle time

Part number	Power consumption Active (MAX.)	Access time (MAX.)	R/W cycle time (MIN.)	EDO (Hyper page mode) cycle time (MIN.)
★ μPD42S17405L-A50, 4217405L-A50	660 mW	50 ns	84 ns	20 ns
μPD42S17405L-A60, 4217405L-A60	360 mW	60 ns	104 ns	25 ns
μPD42S17405L-A70, 4217405L-A70	324 mW	70 ns	124 ns	30 ns

- μPD42S17405L can execute $\overline{CAS}$ before $\overline{RAS}$ self refresh

Part number	Refresh cycle	Refresh	Power consumption at standby (MAX.)
μPD42S17405L	2,048 cycles/128 ms	$\overline{CAS}$ before $\overline{RAS}$ self refresh $\overline{CAS}$ before $\overline{RAS}$ refresh $\overline{RAS}$ only refresh Hidden refresh	0.54 mW (CMOS level input)
μPD4217405L	2,048 cycles/32 ms	$\overline{CAS}$ before $\overline{RAS}$ refresh $\overline{RAS}$ only refresh Hidden refresh	1.8 mW (CMOS level input)

The information in this document is subject to change without notice.

Document No. M10068EJ6V0DS00 (6th edition)
Date Published January 1997 N
Printed in Japan

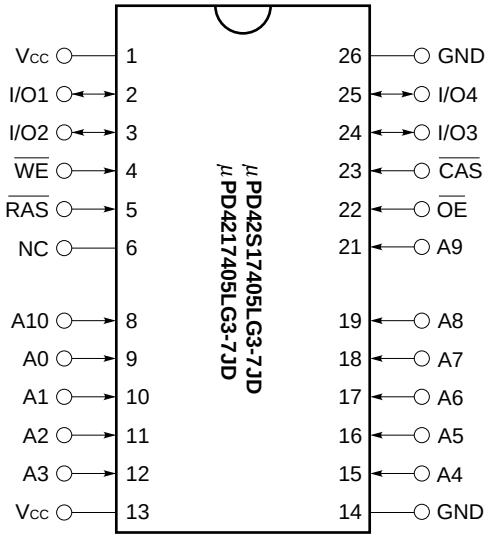
The mark ★ shows major revised points.

★ Ordering Information

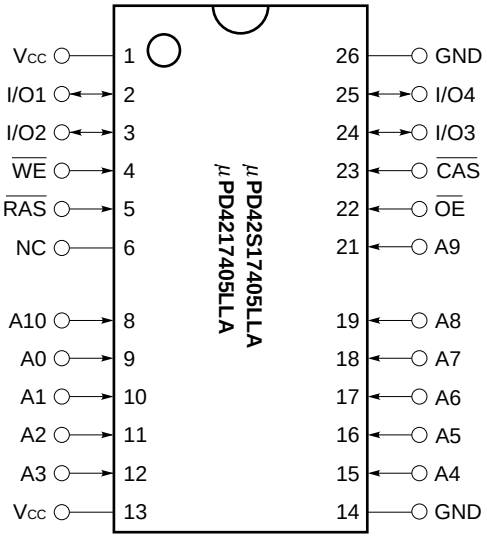
Part number	Access time (MAX.)	Package	Refresh
μPD42S17405LG3-A50-7JD	50 ns	26-pin plastic TSOP (II) (300 mil)	$\overline{CAS}$ before $\overline{RAS}$ self refresh $\overline{CAS}$ before $\overline{RAS}$ refresh $\overline{RAS}$ only refresh Hidden refresh
μPD42S17405LG3-A60-7JD	60 ns		
μPD42S17405LG3-A70-7JD	70 ns		
μPD42S17405LLA-A50	50 ns	26-pin plastic SOJ (300 mil)	
μPD42S17405LLA-A60	60 ns		
μPD42S17405LLA-A70	70 ns		
μPD4217405LG3-A50-7JD	50 ns	26-pin plastic TSOP (II) (300 mil)	$\overline{CAS}$ before $\overline{RAS}$ refresh $\overline{RAS}$ only refresh Hidden refresh
μPD4217405LG3-A60-7JD	60 ns		
μPD4217405LG3-A70-7JD	70 ns		
μPD4217405LLA-A50	50 ns	26-pin plastic SOJ (300 mil)	
μPD4217405LLA-A60	60 ns		
μPD4217405LLA-A70	70 ns		

Pin Configurations (Marking Side)

26-pin Plastic TSOP (II) (300 mil)

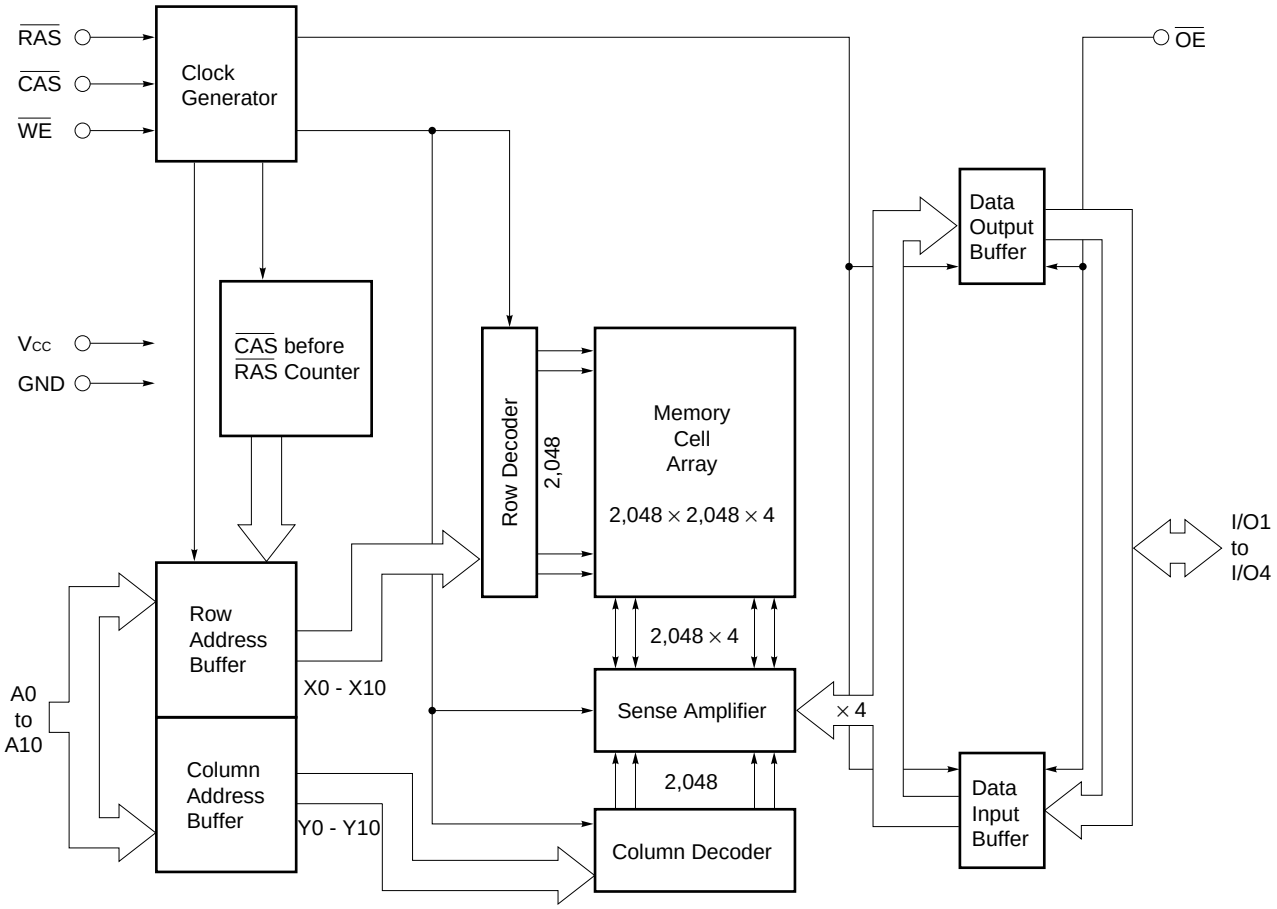


26-pin Plastic SOJ (300 mil)



A0 to A10 : Address Inputs
I/O1 to I/O4: Data Inputs/Outputs
$\overline{RAS}$: Row Address Strobe
$\overline{CAS}$: Column Address Strobe
$\overline{WE}$: Write Enable
$\overline{OE}$: Output Enable
V_{CC} : Power Supply
GND : Ground
NC : No Connection

Block Diagram



Input/Output Pin Functions

The μPD42S17405L, 4217405L have input pins $\overline{RAS}$, $\overline{CAS}$, $\overline{WE}$, $\overline{OE}$, A0 to A10 and input/output pins I/O1 to I/O4.

Pin name	Input/Output	Function
$\overline{RAS}$ (Row address strobe)	Input	$\overline{RAS}$ activates the sense amplifier by latching a row address and selecting a corresponding word line. It refreshes memory cell array of one line selected by the row address. It also selects the following function. • $\overline{CAS}$ before $\overline{RAS}$ refresh
$\overline{CAS}$ (Column address strobe)	Input	$\overline{CAS}$ activates data input/output circuit by latching column address and selecting a digit line connected with the sense amplifier.
A0 to A10 (Address inputs)	Input	Address bus. Input total 22-bit of address signal, upper 11-bit and lower 11-bit in sequence (address multiplex method). Therefore, one word is selected from 4,194,304-word by 4-bit memory cell array. In actual operation, latch row address by specifying row address and activating $\overline{RAS}$. Then, switch the address bus to column address and activate $\overline{CAS}$. Each address is taken into the device when $\overline{RAS}$ and $\overline{CAS}$ are activated. Therefore, the address input setup time (t_{ASR}, t_{ASC}) and hold time (t_{RAH}, t_{CAH}) are specified for the activation of $\overline{RAS}$ and $\overline{CAS}$.
$\overline{WE}$ (Write enable)	Input	Write control signal. Write operation is executed by activating $\overline{RAS}$, $\overline{CAS}$ and $\overline{WE}$.
$\overline{OE}$ (Output enable)	Input	Read control signal. Read operation can be executed by activating $\overline{RAS}$, $\overline{CAS}$ and $\overline{OE}$. If $\overline{WE}$ is activated during read operation, $\overline{OE}$ is to be ineffective in the device. Therefore, read operation cannot be executed.
I/O1 to I/O4 (Data inputs/outputs)	Input/Output	4-bit data bus. I/O1 to I/O4 are used to input/output data.

Hyper Page Mode (EDO)

The hyper page mode (EDO) is a kind of page mode with enhanced features. The two major features of the hyper page mode (EDO) are as follows.

1. Data output time is extended.

In the hyper page mode (EDO), the output data is held to the next $\overline{CAS}$ cycle's falling edge, instead of the rising edge. For this reason, valid data output time in the hyper page mode (EDO) is extended compared with the fast page mode (= data extend function). In the fast page mode, the data output time becomes shorter as the $\overline{CAS}$ cycle time becomes shorter. Therefore, in the hyper page mode (EDO), the timing margin in read cycle is larger than that of the fast page mode even if the $\overline{CAS}$ cycle time becomes shorter.

2. The $\overline{CAS}$ cycle time in the hyper page mode (EDO) is shorter than that in the fast page mode.

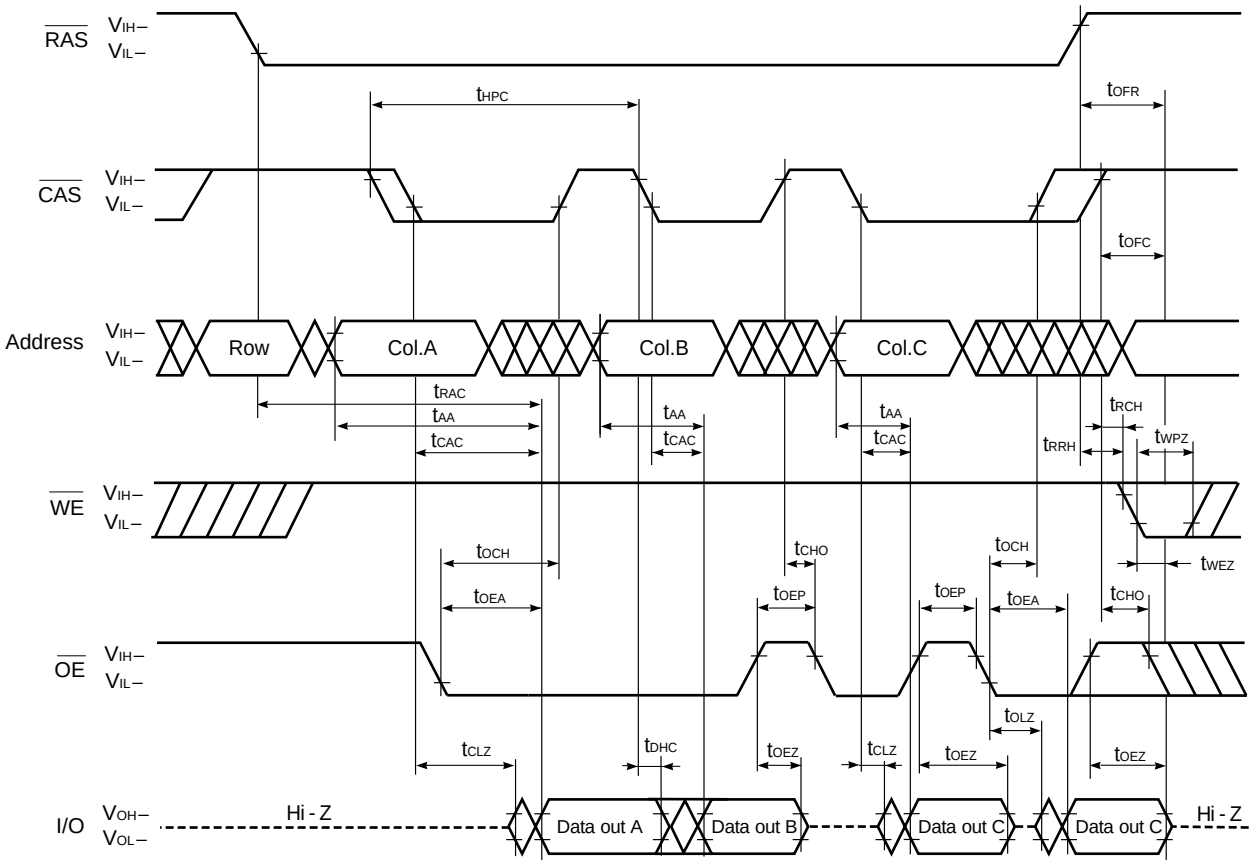
In the hyper page mode (EDO), due to the data extend function, the $\overline{CAS}$ cycle time can be shorter than in the fast page mode if the timing margin is the same.

Taking a device whose t_{RAC} is 60 ns as an example, the $\overline{CAS}$ cycle time in the fast page mode is 25 ns while that in the fast page mode is 40 ns.

In the hyper page mode (EDO), read (data out) and write (data in) cycles can be executed repeatedly during one $\overline{RAS}$ cycle. The hyper page mode (EDO) allows both read and write operations during one cycle.

The following shows a part of the hyper page mode (EDO) read cycle. Specifications to be observed are described in the next page.

Hyper Page Mode (EDO) Read Cycle



Cautions when using the hyper page mode (EDO)

1. $\overline{CAS}$ access should be used to operate t_{HPC} at the MIN. value.

2. To make I/Os to Hi-Z in read cycle, it is necessary to control $\overline{RAS}$, $\overline{CAS}$, $\overline{WE}$, $\overline{OE}$ as follows. The effective specification depends on the state of each signal.

(1) Both $\overline{RAS}$ and $\overline{CAS}$ are inactive (at the end of read cycle)

$\overline{WE}$: inactive, $\overline{OE}$: active

t_{OFC} is effective when $\overline{RAS}$ is inactivated before $\overline{CAS}$ is inactivated.

t_{OFR} is effective when $\overline{CAS}$ is inactivated before $\overline{RAS}$ is inactivated.

The slower of t_{OFC} and t_{OFR} becomes effective.

(2) Both $\overline{RAS}$ and $\overline{CAS}$ are active or either $\overline{RAS}$ or $\overline{CAS}$ is active (in read cycle)

$\overline{WE}$, $\overline{OE}$: inactive ····· t_{OEZ} is effective.

Both $\overline{RAS}$ and $\overline{CAS}$ are inactive or $\overline{RAS}$ is active and $\overline{CAS}$ is inactive (at the end of read cycle)

$\overline{WE}$, $\overline{OE}$: active and either t_{RRH} or t_{RCH} must be met ····· t_{WEZ} and t_{WPZ} are effective.

The faster of t_{OEZ} and t_{WEZ} becomes effective.

The faster of (1) and (2) becomes effective.

3. In read cycle, the effective specification depends on the state of $\overline{CAS}$ signal when controlling data output with the $\overline{OE}$ signal.

(1) $\overline{CAS}$: inactive, $\overline{OE}$: active ····· t_{OHO} is effective.

(2) $\overline{CAS}$, $\overline{OE}$: active ····· t_{OCH} is effective.

Electrical Specifications

- All voltages are referenced to GND.
- After power up ($V_{CC} \geq V_{CC\ (MIN.)}$), wait more than 100 μs ($\overline{RAS}$, $\overline{CAS}$ inactive) and then, execute eight $\overline{CAS}$ before $\overline{RAS}$ or $\overline{RAS}$ only refresh cycles as dummy cycles to initialize internal circuit.

Absolute Maximum Ratings

Parameter	Symbol	Condition	Rating	Unit
Voltage on any pin relative to GND	V_T		–0.5 to +4.6	V
Supply voltage	V_{CC}		–0.5 to +4.6	V
Output current	I_O		20	mA
Power dissipation	P_D		1	W
Operating ambient temperature	T_A		0 to +70	˚C
Storage temperature	T_{stg}		–55 to +125	˚C

Caution Exposing the device to stress above those listed in Absolute Maximum Ratings could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
Supply voltage	V_{CC}		3.0	3.3	3.6	V
High level input voltage	V_{IH}		2.0		V_{CC} + 0.3	V
Low level input voltage	V_{IL}		–0.3		+0.8	V
Operating ambient temperature	T_A		0		70	˚C

Capacitance (T_A = 25 ˚C, f = 1 MHz)

Parameter	Symbol	Test condition	MIN.	TYP.	MAX.	Unit
Input capacitance	C_{I1}	Address			5	pF
	C_{I2}	$\overline{RAS}$, $\overline{CAS}$, $\overline{WE}$, $\overline{OE}$			7	
Data input/output capacitance	$C_{I/O}$	I/O			7	pF

★ **DC Characteristics (Recommended operating conditions unless otherwise noted)**

Parameter		Symbol	Test condition		MIN.	MAX.	Unit	Notes
Operating current		I_{CC1}	$\overline{RAS}$, $\overline{CAS}$ cycling $t_{RC} = t_{RC\ (MIN.)}$, I_O = 0 mA	t_{RAC} = 50 ns		120	mA	1, 2, 3
				t_{RAC} = 60 ns		100		
				t_{RAC} = 70 ns		90		
Standby current	μPD42S17405L	I_{CC2}	$\overline{RAS}$, $\overline{CAS} \geq V_{IH\ (MIN.)}$, I_O = 0 mA			0.5	mA	
			$\overline{RAS}$, $\overline{CAS} \geq V_{CC}$ – 0.2 V, I_O = 0 mA			0.15		
	μPD4217405L		$\overline{RAS}$, $\overline{CAS} \geq V_{IH\ (MIN.)}$, I_O = 0 mA			2.0		
			$\overline{RAS}$, $\overline{CAS} \geq V_{CC}$ – 0.2 V, I_O = 0 mA			0.5		
$\overline{RAS}$ only refresh current		I_{CC3}	$\overline{RAS}$ cycling, $\overline{CAS} \geq V_{IH\ (MIN.)}$ $t_{RC} = t_{RC\ (MIN.)}$, I_O = 0 mA	t_{RAC} = 50 ns		120	mA	1, 2, 3 ,4
				t_{RAC} = 60 ns		100		
				t_{RAC} = 70 ns		90		
Operating current (Hyper page mode (EDO))		I_{CC4}	$\overline{RAS} \leq V_{IL\ (MAX.)}$, $\overline{CAS}$ cycling $t_{HPC} = t_{HPC\ (MIN.)}$, I_O = 0 mA	t_{RAC} = 50 ns		100	mA	1, 2, 5
				t_{RAC} = 60 ns		90		
				t_{RAC} = 70 ns		80		
$\overline{CAS}$ before $\overline{RAS}$ refresh current		I_{CC5}	$\overline{RAS}$ cycling $t_{RC} = t_{RC\ (MIN.)}$, I_O = 0 mA	t_{RAC} = 50 ns		120	mA	1, 2
				t_{RAC} = 60 ns		100		
				t_{RAC} = 70 ns		90		
$\overline{CAS}$ before $\overline{RAS}$ long refresh current (2,048 cycles / 128 ms, only for the μPD42S17405L)		I_{CC6}	$\overline{CAS}$ before $\overline{RAS}$ refresh: t_{RC} = 62.5 μs $\overline{RAS}$, $\overline{CAS}$: V_{CC} – 0.2 V ≤ V_{IH} ≤ $V_{IH\ (MAX.)}$ 0 V ≤ V_{IL} ≤ 0.2 V	$t_{RAS} \leq$ 300 ns		400	μA	1, 2
			Standby: $\overline{RAS}$, $\overline{CAS} \geq V_{CC}$ – 0.2 V Address: V_{IH} or V_{IL} $\overline{WE}$, $\overline{OE}$: V_{IH} I_O = 0 mA	$t_{RAS} \leq$ 1 μs		450	μA	1, 2
$\overline{CAS}$ before $\overline{RAS}$ self refresh current (only for the μPD42S17405L)		I_{CC7}	$\overline{RAS}$, $\overline{CAS}$: t_{RASS} = 5 ms V_{CC} – 0.2 V ≤ V_{IH} ≤ $V_{IH\ (MAX.)}$ 0 V ≤ V_{IL} ≤ 0.2 V I_O = 0 mA			200	μA	2
Input leakage current		$I_{I\ (L)}$	V_I = 0 to 3.6 V All other pins not under test = 0 V		–5	+5	μA	
Output leakage current		$I_{O\ (L)}$	V_O = 0 to 3.6 V Output is disabled (Hi-Z)		–5	+5	μA	
High level output voltage		V_{OH}	I_O = –2.0 mA		2.4		V	
Low level output voltage		V_{OL}	I_O = +2.0 mA			0.4	V	

Notes 1. I_{CC1}, I_{CC3}, I_{CC4}, I_{CC5} and I_{CC6} depend on cycle rates (t_{RC} and t_{HPC}).

2. Specified values are obtained with outputs unloaded.

3. I_{CC1} and I_{CC3} are measured assuming that address can be changed once or less during $\overline{RAS} \leq V_{IL\ (MAX.)}$ and $\overline{CAS} \geq V_{IH\ (MIN.)}$.

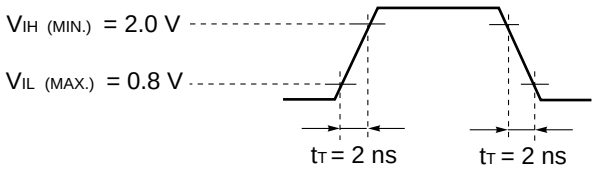
4. I_{CC3} is measured assuming that all column address inputs are held at either high or low.

5. I_{CC4} is measured assuming that all column address inputs are switched only once during each hyper page (EDO) cycle.

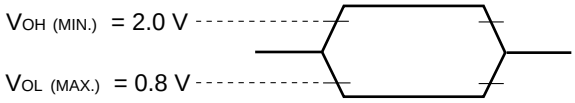
★ AC Characteristics (Recommended Operating Conditions unless otherwise noted)

AC Characteristics Test Conditions

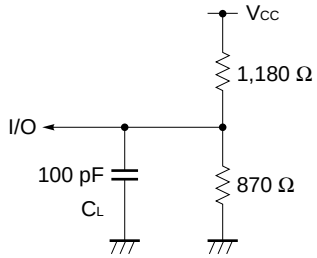
(1) Input timing specification



(2) Output timing specification



(3) Output load condition



Common to Read, Write, Read Modify Write Cycle

Parameter		Symbol	t_{RAC} = 50 ns		t_{RAC} = 60 ns		t_{RAC} = 70 ns		Unit	Notes
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read / Write cycle time		t_{RC}	84	–	104	–	124	–	ns	
$\overline{RAS}$ precharge time		t_{RP}	30	–	40	–	50	–	ns	
$\overline{CAS}$ precharge time		t_{CPN}	7	–	10	–	10	–	ns	
$\overline{RAS}$ pulse width		t_{RAS}	50	10,000	60	10,000	70	10,000	ns	1
$\overline{CAS}$ pulse width		t_{CAS}	7	10,000	10	10,000	12	10,000	ns	
$\overline{RAS}$ hold time		t_{RSH}	10	–	15	–	20	–	ns	
$\overline{CAS}$ hold time		t_{CSH}	38	–	45	–	50	–	ns	
$\overline{RAS}$ to $\overline{CAS}$ delay time		t_{RCD}	11	37	14	45	14	52	ns	2
$\overline{RAS}$ to column address delay time		t_{RAD}	9	25	12	30	12	35	ns	2
$\overline{CAS}$ to $\overline{RAS}$ precharge time		t_{CRP}	5	–	5	–	5	–	ns	3
Row address setup time		t_{ASR}	0	–	0	–	0	–	ns	
Row address hold time		t_{RAH}	7	–	10	–	10	–	ns	
Column address setup time		t_{ASC}	0	–	0	–	0	–	ns	
Column address hold time		t_{CAH}	7	–	10	–	12	–	ns	
$\overline{OE}$ lead time referenced to $\overline{RAS}$		t_{OES}	0	–	0	–	0	–	ns	
$\overline{CAS}$ to data setup time		t_{CLZ}	0	–	0	–	0	–	ns	
$\overline{OE}$ to data setup time		t_{OLZ}	0	–	0	–	0	–	ns	
$\overline{OE}$ to data delay time		t_{OED}	10	–	13	–	15	–	ns	
Transition time (rise and fall)		t_T	1	50	1	50	1	50	ns	
Refresh time	μPD42S17405L	t_{REF}	–	128	–	128	–	128	ms	4
	μPD4217405L		–	32	–	32	–	32		

Notes 1. In $\overline{CAS}$ before $\overline{RAS}$ refresh cycles, $t_{RAS\ (MAX.)}$ is 100 μs.
If 10 μs < t_{RAS} < 100 μs, $\overline{RAS}$ precharge time for $\overline{CAS}$ before $\overline{RAS}$ self refresh (t_{RPS}) is applied.

2. For read cycles, access time is defined as follows:

Input conditions	Access time	Access time from $\overline{RAS}$
$t_{RAD} \leq t_{RAD\ (MAX.)}$ and $t_{RCD} \leq t_{RCD\ (MAX.)}$	$t_{RAC\ (MAX.)}$	$t_{RAC\ (MAX.)}$
$t_{RAD} > t_{RAD\ (MAX.)}$ and $t_{RCD} \leq t_{RCD\ (MAX.)}$	$t_{AA\ (MAX.)}$	$t_{RAD} + t_{AA\ (MAX.)}$
$t_{RCD} > t_{RCD\ (MAX.)}$	$t_{CAC\ (MAX.)}$	$t_{RCD} + t_{CAC\ (MAX.)}$

$t_{RAD\ (MAX.)}$ and $t_{RCD\ (MAX.)}$ are specified as reference points only ; they are not restrictive operating parameters. They are used to determine which access time (t_{RAC}, t_{AA} or t_{CAC}) is to be used for finding out when output data will be available. Therefore, the input conditions $t_{RAD} \geq t_{RAD\ (MAX.)}$ and $t_{RCD} \geq t_{RCD\ (MAX.)}$ will not cause any operation problems.

3. $t_{CRP\ (MIN.)}$ requirement is applied to $\overline{RAS}$, $\overline{CAS}$ cycles.

4. This specification is applied only to the μPD42S17405L.

Read Cycle

Parameter	Symbol	t_{RAC} = 50 ns		t_{RAC} = 60 ns		t_{RAC} = 70 ns		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Access time from $\overline{RAS}$	t_{RAC}	–	50	–	60	–	70	ns	1
Access time from $\overline{CAS}$	t_{CAC}	–	13	–	15	–	18	ns	1
Access time from column address	t_{AA}	–	25	–	30	–	35	ns	1
Access time from $\overline{OE}$	t_{OEA}	–	13	–	15	–	18	ns	
Column address lead time referenced to $\overline{RAS}$	t_{RAL}	25	–	30	–	35	–	ns	
Read command setup time	t_{RCS}	0	–	0	–	0	–	ns	
Read command hold time referenced to $\overline{RAS}$	t_{RRH}	0	–	0	–	0	–	ns	2
Read command hold time referenced to $\overline{CAS}$	t_{RCH}	0	–	0	–	0	–	ns	2
Output buffer turn-off delay time from $\overline{OE}$	t_{OEZ}	0	10	0	13	0	15	ns	3
$\overline{CAS}$ hold time to $\overline{OE}$	t_{CHO}	5	–	5	–	5	–	ns	4

Notes 1. For read cycles, access time is defined as follows:

Input conditions	Access time	Access time from $\overline{RAS}$
$t_{RAD} \leq t_{RAD\ (MAX.)}$ and $t_{RCD} \leq t_{RCD\ (MAX.)}$	$t_{RAC\ (MAX.)}$	$t_{RAC\ (MAX.)}$
$t_{RAD} > t_{RAD\ (MAX.)}$ and $t_{RCD} \leq t_{RCD\ (MAX.)}$	$t_{AA\ (MAX.)}$	$t_{RAD} + t_{AA\ (MAX.)}$
$t_{RCD} > t_{RCD\ (MAX.)}$	$t_{CAC\ (MAX.)}$	$t_{RCD} + t_{CAC\ (MAX.)}$

$t_{RAD\ (MAX.)}$ and $t_{RCD\ (MAX.)}$ are specified as reference points only; they are not restrictive operating parameters. They are used to determine which access time (t_{RAC}, t_{AA} or t_{CAC}) is to be used for finding out when output data will be available. Therefore, the input conditions $t_{RAD} \geq t_{RAD\ (MAX.)}$ and $t_{RCD} \geq t_{RCD\ (MAX.)}$ will not cause any operation problems.

2. Either $t_{RCH\ (MIN.)}$ or $t_{RRH\ (MIN.)}$ should be met in read cycles.

3. $t_{OEZ(MAX.)}$ defines the time when the output achieves the condition of Hi-Z and is not referenced to V_{OH} or V_{OL}.

4. $\overline{WE}$: inactive (in read cycle)
$\overline{CAS}$: inactive, $\overline{OE}$: active ····· t_{CHO} is effective.
$\overline{CAS}$, $\overline{OE}$: active ····· t_{CH} is effective.

Write Cycle

Parameter	Symbol	t_{RAC} = 50 ns		t_{RAC} = 60 ns		t_{RAC} = 70 ns		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
$\overline{WE}$ hold time referenced to $\overline{CAS}$	t_{WCH}	7	–	10	–	10	–	ns	1
$\overline{WE}$ pulse width	t_{WP}	7	–	10	–	10	–	ns	1
$\overline{WE}$ lead time referenced to $\overline{RAS}$	t_{RWL}	10	–	15	–	20	–	ns	
$\overline{WE}$ lead time referenced to $\overline{CAS}$	t_{CWL}	7	–	10	–	12	–	ns	
$\overline{WE}$ setup time	t_{WCS}	0	–	0	–	0	–	ns	2
$\overline{OE}$ hold time	t_{OEH}	0	–	0	–	0	–	ns	
Data-in setup time	t_{DS}	0	–	0	–	0	–	ns	3
Data-in hold time	t_{DH}	7	–	10	–	10	–	ns	3

Notes 1. $t_{WP\ (MIN.)}$ is applied to late write cycles or read modify write cycles. In early write cycles, $t_{WCH\ (MIN.)}$ should be met.

2. If $t_{WCS} \geq t_{WCS\ (MIN.)}$, the cycle is an early write cycle and the data out will remain Hi-Z through the entire cycle.

3. $t_{DS\ (MIN.)}$ and $t_{DH\ (MIN.)}$ are referenced to the $\overline{CAS}$ falling edge in early write cycles. In late write cycles and read modify write cycles, they are referenced to the $\overline{WE}$ falling edge.

Read Modify Write Cycle

Parameter	Symbol	t_{RAC} = 50 ns		t_{RAC} = 60 ns		t_{RAC} = 70 ns		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read modify write cycle time	t_{RWC}	107	–	133	–	157	–	ns	
$\overline{RAS}$ to $\overline{WE}$ delay time	t_{RWD}	64	–	77	–	89	–	ns	1
$\overline{CAS}$ to $\overline{WE}$ delay time	t_{CWD}	27	–	32	–	37	–	ns	1
Column address to $\overline{WE}$ delay time	t_{AWD}	39	–	47	–	54	–	ns	1

Note 1. If $t_{WCS} \geq t_{WCS\ (MIN.)}$, the cycle is an early write cycle and the data out will remain Hi-Z through the entire cycle. If $t_{RWD} \geq t_{RWD\ (MIN.)}$, $t_{CWD} \geq t_{CWD\ (MIN.)}$, $t_{AWD} \geq t_{AWD\ (MIN.)}$ and $t_{CPWD} \geq t_{CPWD\ (MIN.)}$, the cycle is a read modify write cycle and the data out will contain data read from the selected cell. If neither of the above conditions is met, the state of the data out is indeterminate.

Hyper Page Mode (EDO)

Parameter	Symbol	t_{RAC} = 50 ns		t_{RAC} = 60 ns		t_{RAC} = 70 ns		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read / Write cycle time	t_{HPC}	20	–	25	–	30	–	ns	1
$\overline{RAS}$ pulse width	t_{RASP}	50	125,000	60	125,000	70	125,000	ns	
$\overline{CAS}$ pulse width	t_{HCAS}	7	10,000	10	10,000	12	10,000	ns	
$\overline{CAS}$ precharge time	t_{CP}	7	–	10	–	10	–	ns	
Access time from $\overline{CAS}$ precharge	t_{ACP}	–	30	–	35	–	40	ns	
$\overline{CAS}$ precharge to $\overline{WE}$ delay time	t_{CPWD}	41	–	52	–	59	–	ns	2
$\overline{RAS}$ hold time from $\overline{CAS}$ precharge	t_{RHCP}	30	–	35	–	40	–	ns	
Read modify write cycle time	t_{HPRWC}	52	–	66	–	75	–	ns	
Data output hold time	t_{DHC}	5	–	5	–	5	–	ns	
$\overline{OE}$ to $\overline{CAS}$ hold time	t_{OCH}	5	–	5	–	5	–	ns	3
$\overline{OE}$ precharge time	t_{OEP}	5	–	5	–	5	–	ns	
Output buffer turn-off delay from $\overline{WE}$	t_{WEZ}	0	10	0	13	0	15	ns	4,5
$\overline{WE}$ pulse width	t_{WPZ}	7	–	10	–	10	–	ns	5
Output buffer turn-off delay from $\overline{RAS}$	t_{OFR}	0	10	0	13	0	15	ns	4,5
Output buffer turn-off delay from $\overline{CAS}$	t_{OFC}	0	10	0	13	0	15	ns	4,5

Notes 1. $t_{HPC\ (MIN.)}$ is applied to $\overline{CAS}$ access.

2. If $t_{WCS} \geq t_{WCS\ (MIN.)}$, the cycle is an early write cycle and the data out will remain Hi-Z through the entire cycle. If $t_{RWD} \geq t_{RWD\ (MIN.)}$, $t_{CWD} \geq t_{CWD\ (MIN.)}$, $t_{AWD} \geq t_{AWD\ (MIN.)}$ and $t_{CPWD} \geq t_{CPWD\ (MIN.)}$, the cycle is a read modify write cycle and the data out will contain data read from the selected cell. If neither of the above conditions is met, the state of the data out is indeterminate.

3. $\overline{WE}$: inactive (in read cycle)
$\overline{CAS}$: inactive, $\overline{OE}$: active ····· t_{CHO} is effective.
$\overline{CAS}$, $\overline{OE}$: active ····· t_{OCH} is effective.

4. $t_{OFC\ (MAX.)}$, $t_{OFR\ (MAX.)}$ and $t_{WEZ\ (MAX.)}$ define the time when the output achieves the conditions of Hi-Z and is not referenced to V_{OH} or V_{OL}.

5. To make I/Os to Hi-Z in read cycle, it is necessary to control $\overline{RAS}$, $\overline{CAS}$, $\overline{WE}$, $\overline{OE}$ as follows. The effective specification depends on state of each signal.

(1) Both $\overline{RAS}$ and $\overline{CAS}$ are inactive (at the end of the read cycle)
$\overline{WE}$: inactive, $\overline{OE}$: active
t_{OFC} is effective when $\overline{RAS}$ is inactivated before $\overline{CAS}$ is inactivated.
t_{OFR} is effective when $\overline{CAS}$ is inactivated before $\overline{RAS}$ is inactivated.
The slower of t_{OFC} and t_{OFR} becomes effective.

(2) Both $\overline{RAS}$ and $\overline{CAS}$ are active or either $\overline{RAS}$ or $\overline{CAS}$ is active (in read cycle)
$\overline{WE}$, $\overline{OE}$: inactive ····· t_{OEZ} is effective.
Both $\overline{RAS}$ and $\overline{CAS}$ are inactive or $\overline{RAS}$ is active and $\overline{CAS}$ is inactive (at the end of read cycle)
$\overline{WE}$, $\overline{OE}$: active and either t_{RRH} or t_{RCH} must be met ····· t_{WEZ} and t_{WPZ} are effective.
The faster of t_{OEZ} and t_{WEZ} becomes effective.

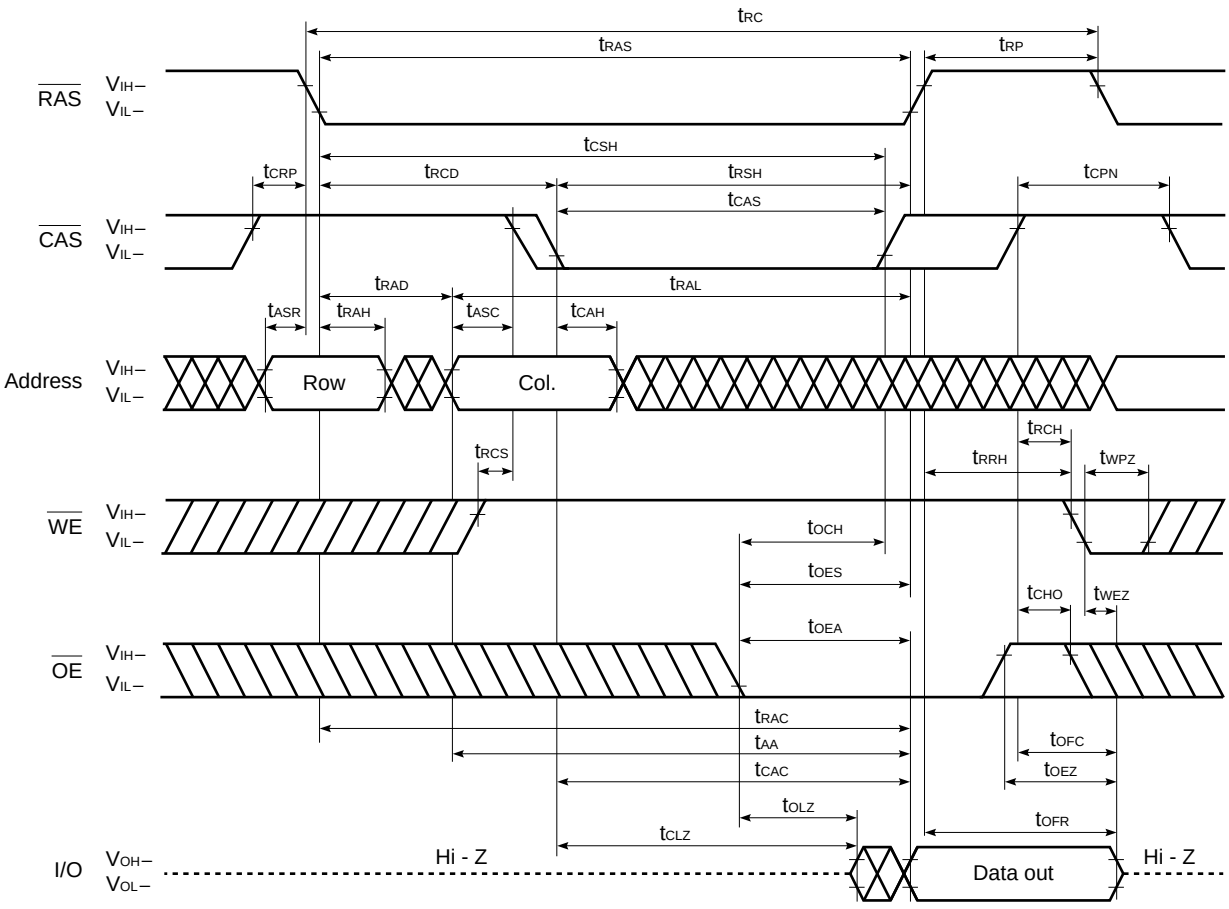
The faster of (1) and (2) becomes effective.

Refresh Cycle

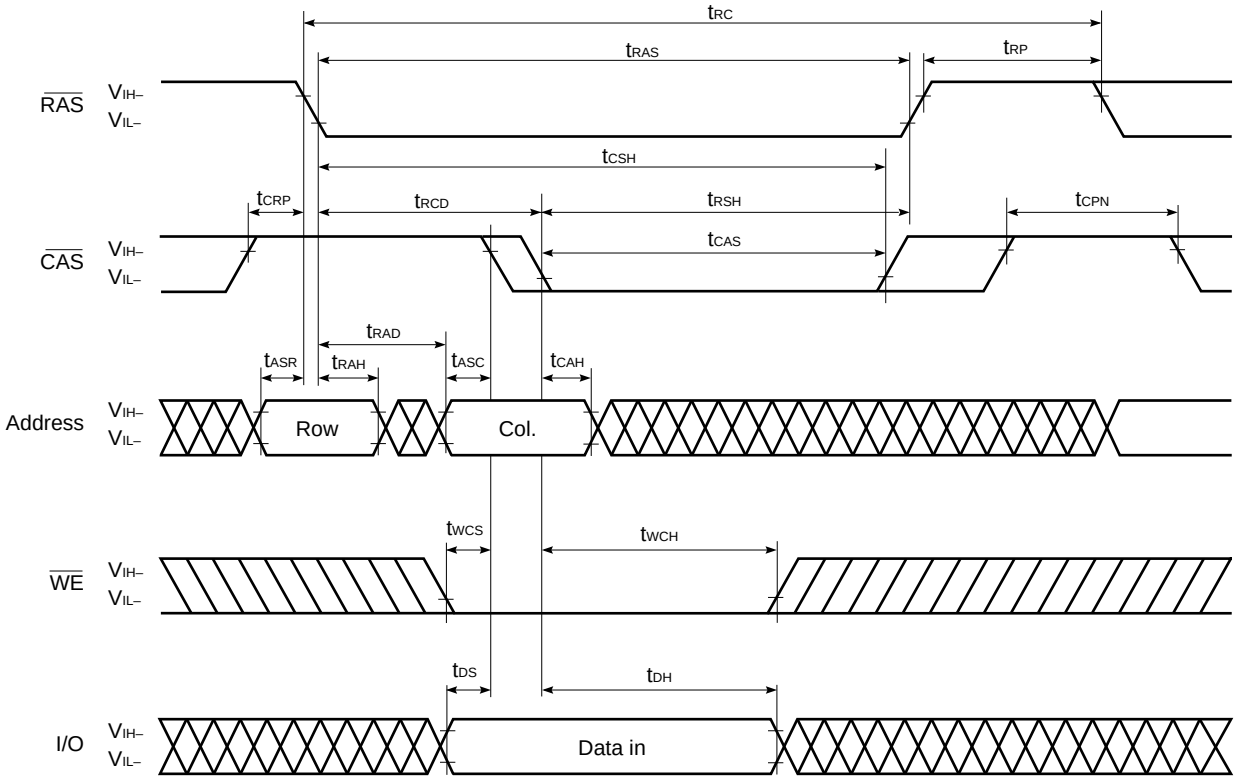
Parameter	Symbol	t_{RAC} = 50 ns		t_{RAC} = 60 ns		t_{RAC} = 70 ns		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
$\overline{CAS}$ setup time	t_{CSR}	5	–	5	–	5	–	ns	
$\overline{CAS}$ hold time ($\overline{CAS}$ before $\overline{RAS}$ refresh)	t_{CHR}	10	–	10	–	10	–	ns	
$\overline{RAS}$ precharge $\overline{CAS}$ hold time	t_{RPC}	5	–	5	–	5	–	ns	
$\overline{RAS}$ pulse width ($\overline{CAS}$ before $\overline{RAS}$ self refresh)	t_{RASS}	100	–	100	–	100	–	μs	1
$\overline{RAS}$ precharge time ($\overline{CAS}$ before $\overline{RAS}$ self refresh)	t_{RPS}	90	–	110	–	130	–	ns	1
$\overline{CAS}$ hold time ($\overline{CAS}$ before $\overline{RAS}$ self refresh)	t_{CHS}	–50	–	–50	–	–50	–	ns	1
$\overline{WE}$ setup time	t_{WSR}	10	–	10	–	10	–	ns	
$\overline{WE}$ hold time	t_{WHR}	15	–	15	–	15	–	ns	

Note 1. This specification is applied only to the μPD42S17405L.

Read Cycle

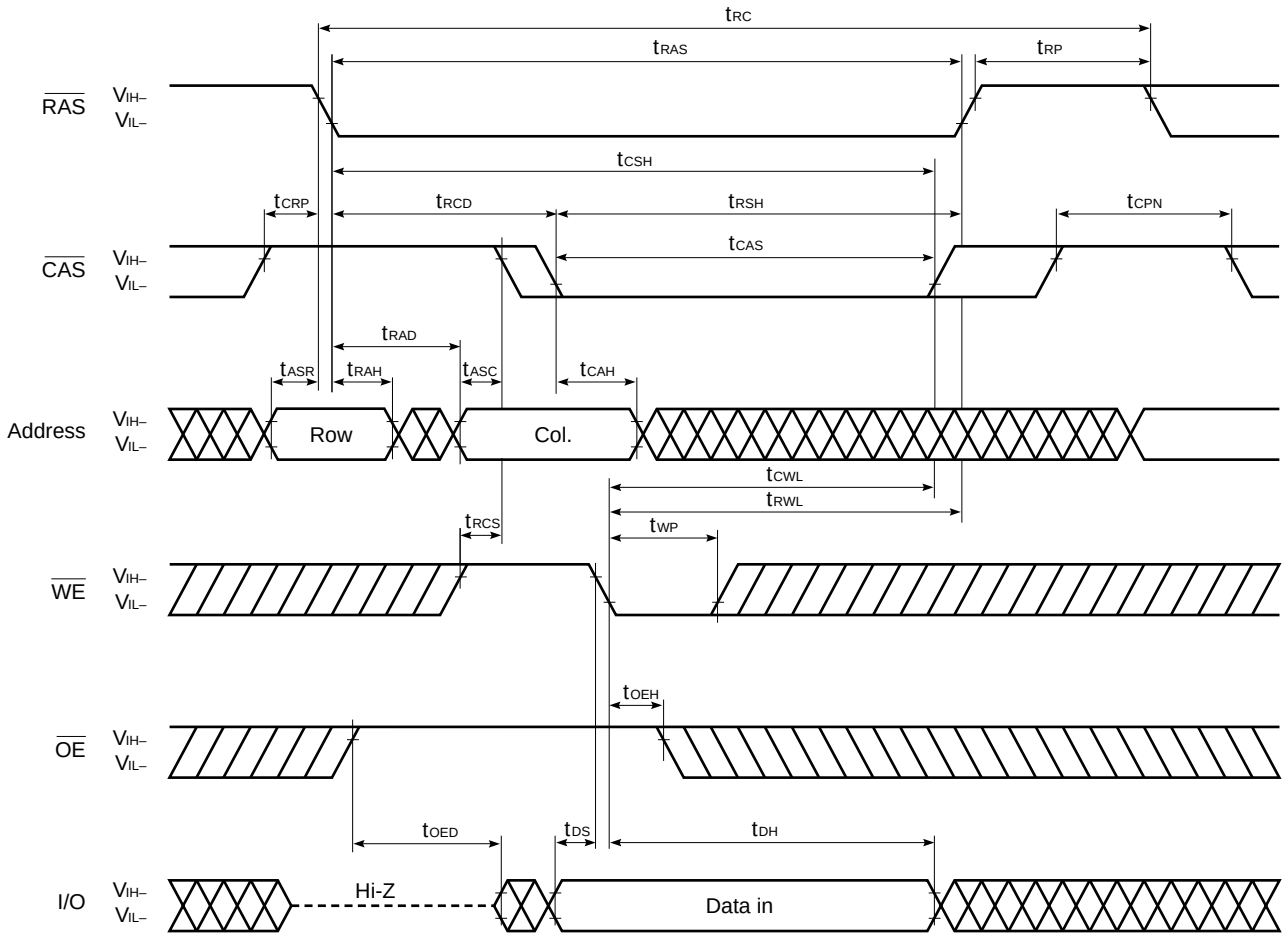

tRC
tRAS
tRP
RAS
VIH–
VIL–
tCSH
tCRP
tRCD
tRSH
tCPN
tCAS
CAS
tRAD
tRAL
tASR
tRAH
tASC
tCAH
Address
Row
Col.
tRCH
tRCS
tRRH
tWPZ
WE
tOCH
tOES
tCHO
tWEZ
tOEA
OE
tRAC
tAA
tOFC
tCAC
tOEZ
tOLZ
tOFR
tCLZ
I/O
VOH–
VOL–
Hi - Z
Data out
Hi - Z

Early Write Cycle

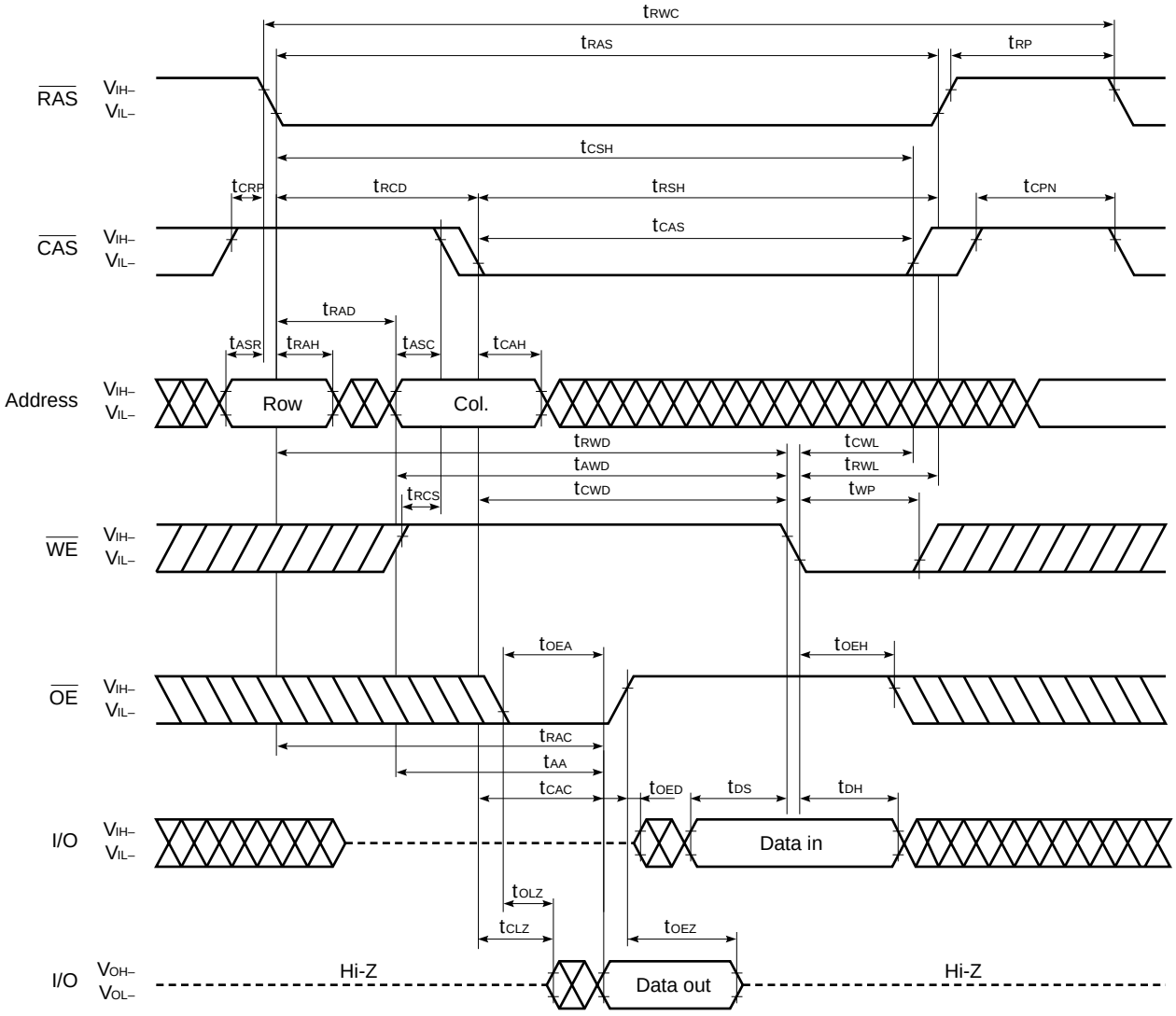


Remark $\overline{OE}$: Don't care

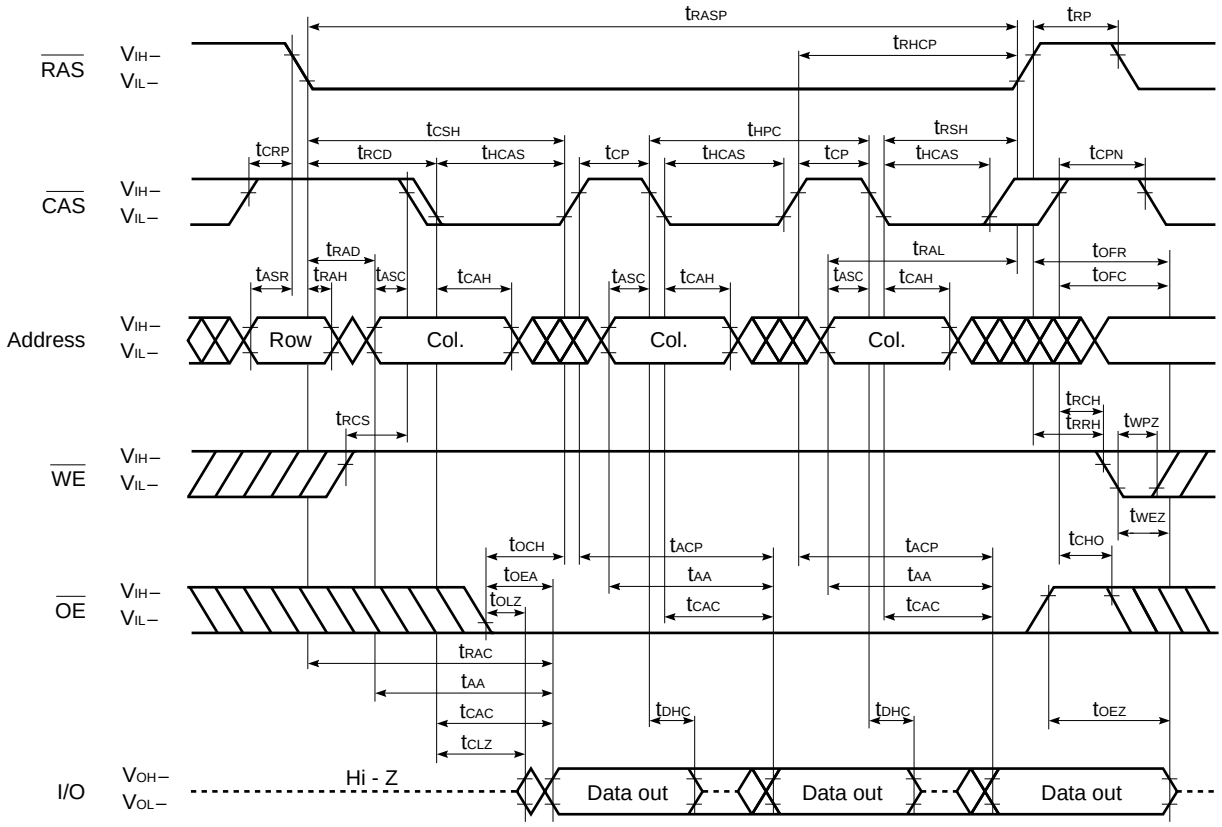
Late Write Cycle



Read Modify Write Cycle

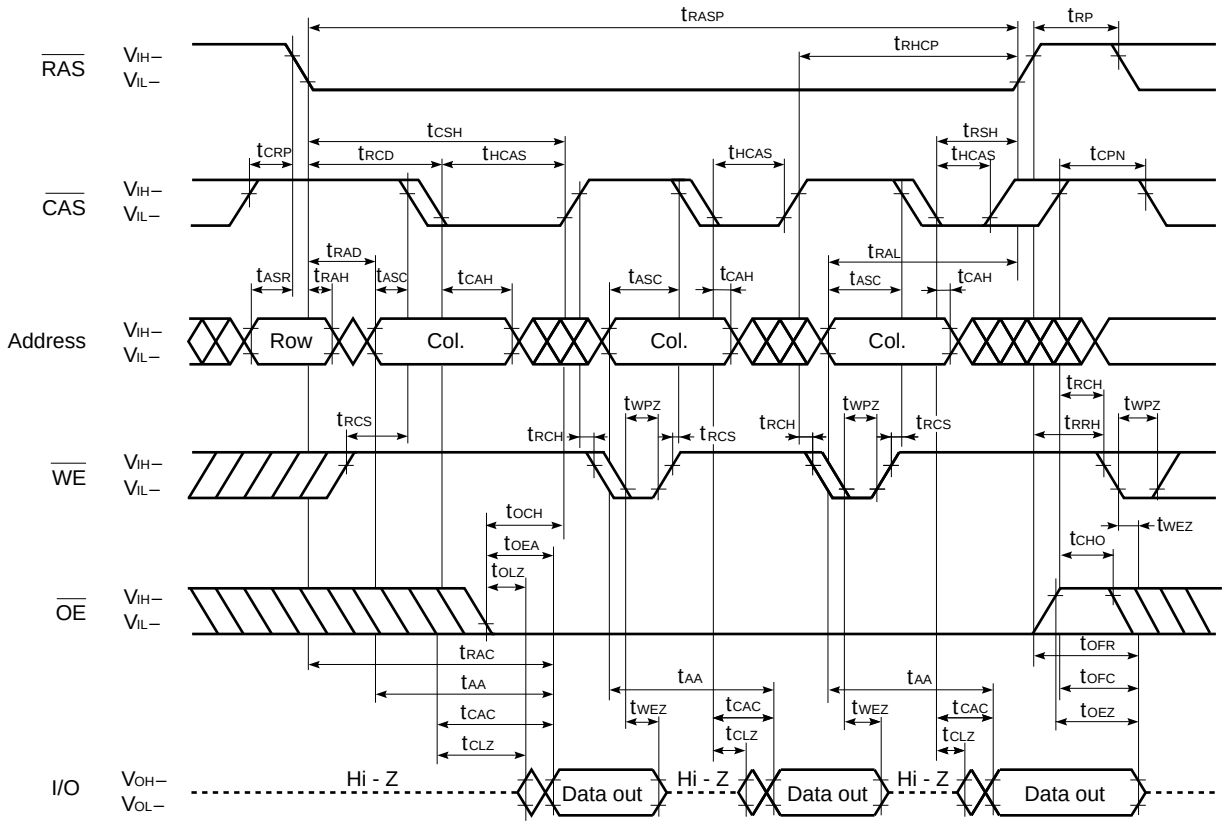


Hyper Page Mode (EDO) Read Cycle



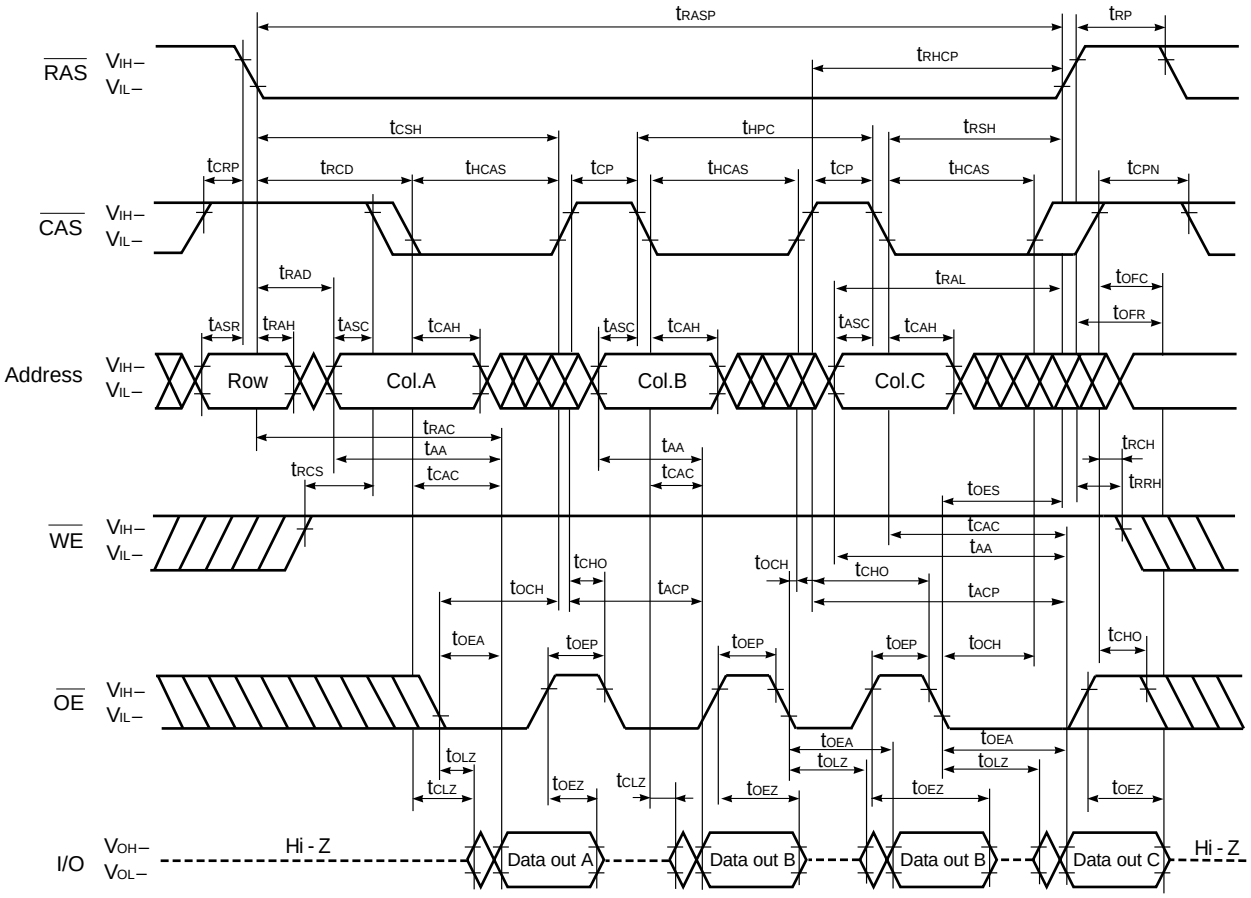
Remark In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive $\overline{CAS}$ cycles within the same $\overline{RAS}$ cycle.

Hyper Page Mode (EDO) Read Cycle ($\overline{WE}$ Control)



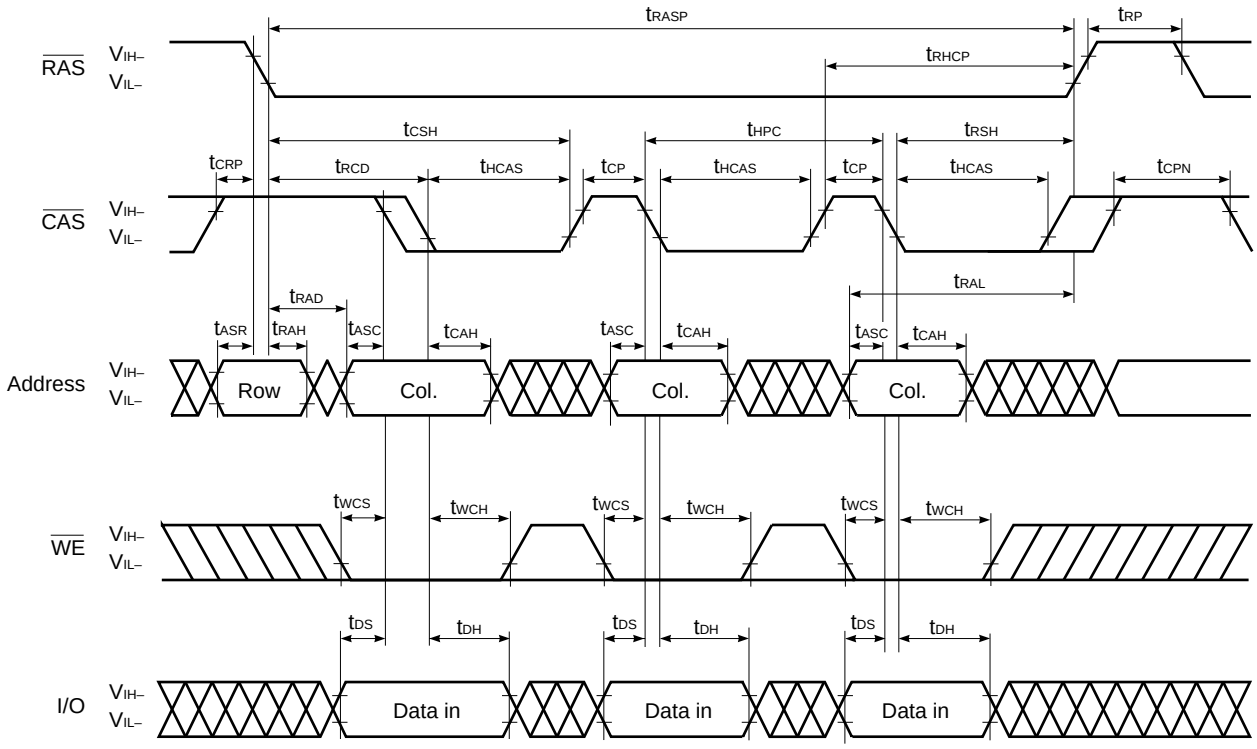
Remark In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive $\overline{CAS}$ cycles within the same $\overline{RAS}$ cycle.

Hyper Page Mode (EDO) Read Cycle ($\overline{OE}$ Control)



Remark In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive $\overline{CAS}$ cycles within the same $\overline{RAS}$ cycle.

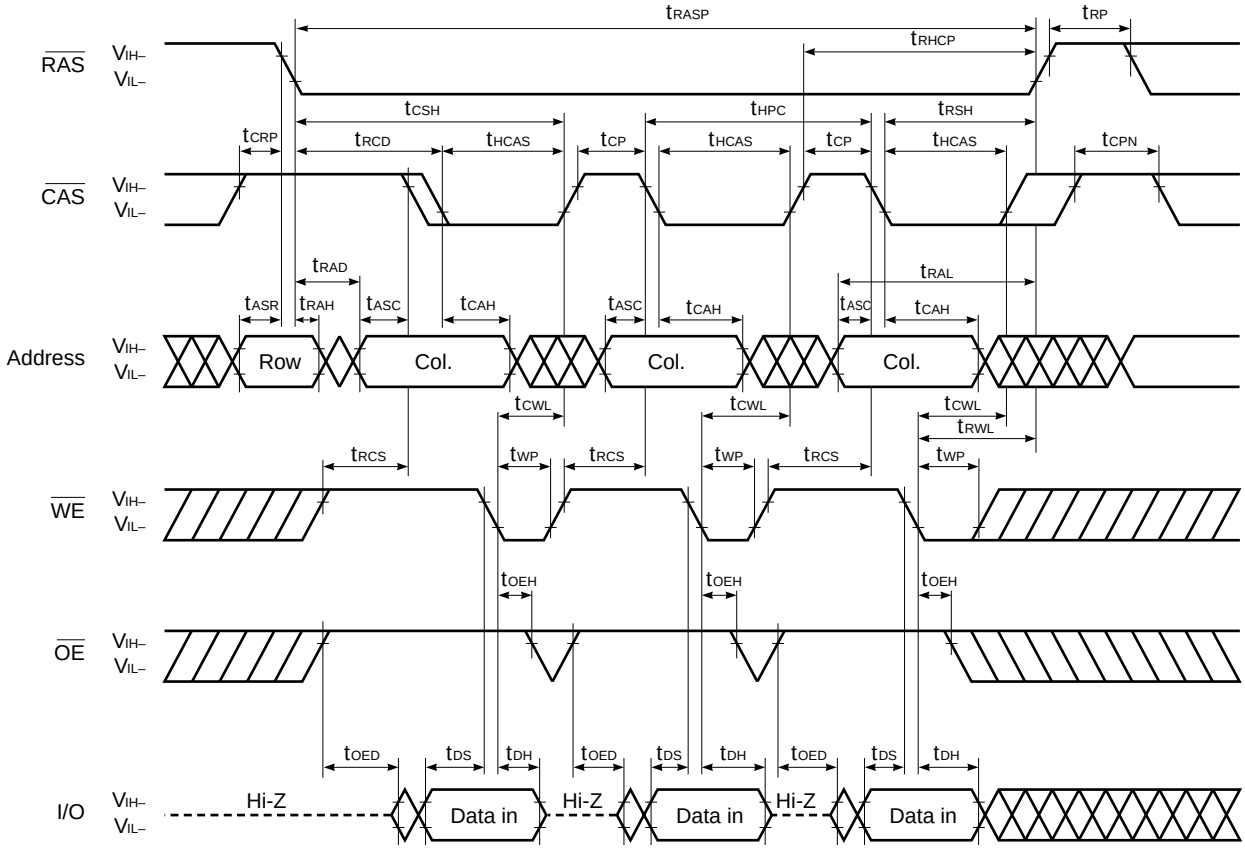
Hyper Page Mode (EDO) Early Write Cycle



Remarks 1. $\overline{OE}$: Don't care

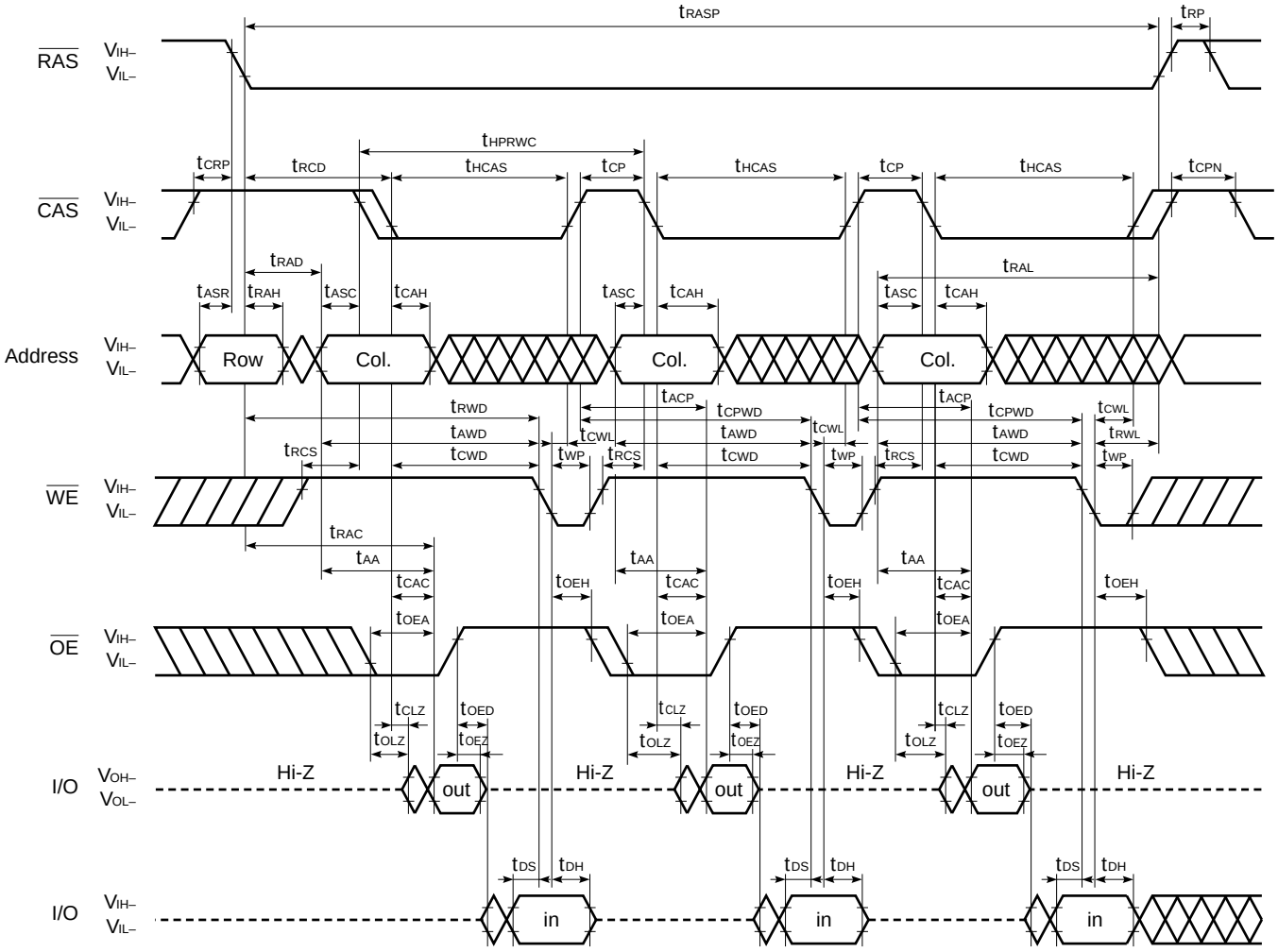
2. In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive $\overline{CAS}$ cycles within the same $\overline{RAS}$ cycle.

Hyper Page Mode (EDO) Late Write Cycle



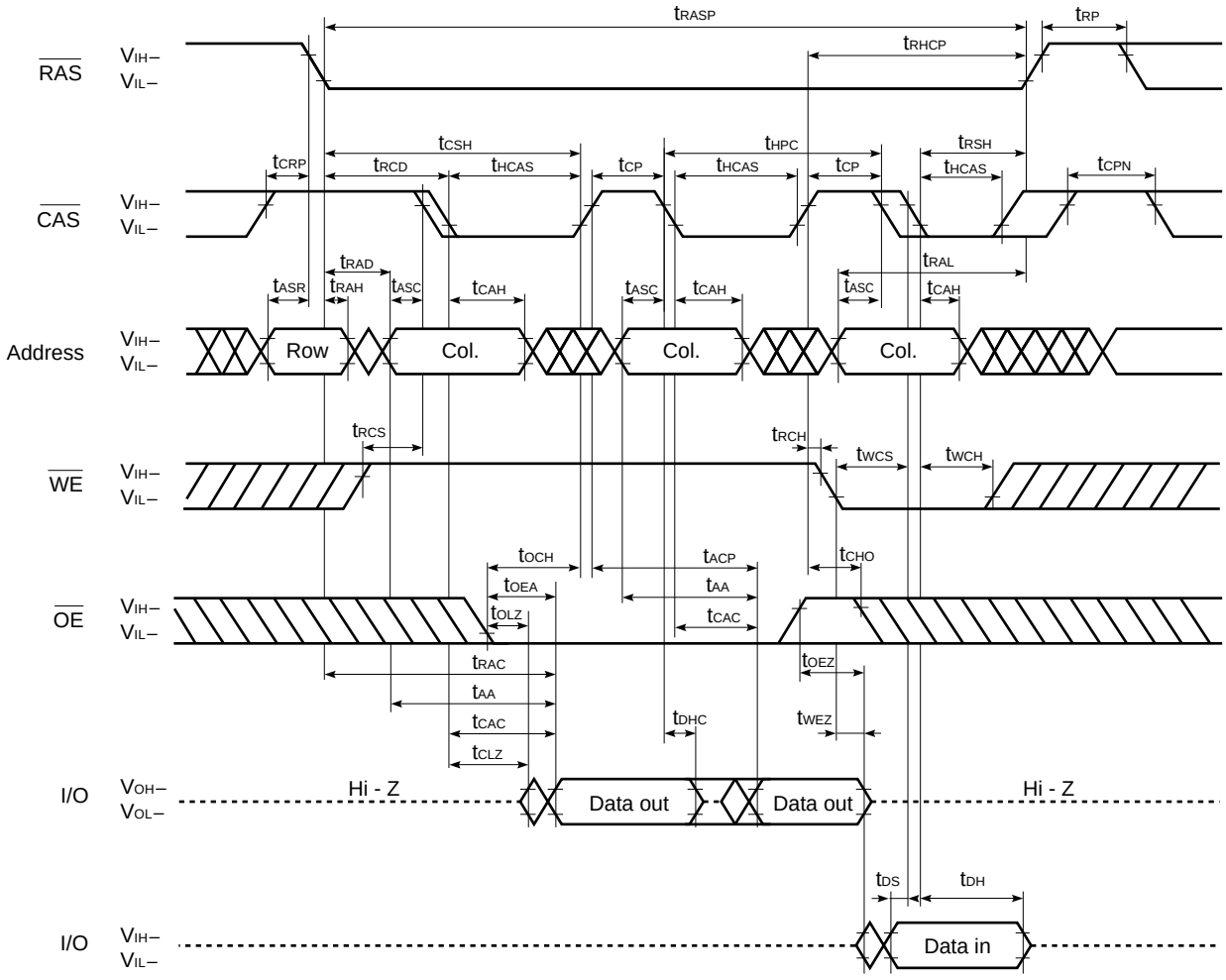
Remark In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive $\overline{CAS}$ cycles within the same $\overline{RAS}$ cycle.

Hyper Page Mode (EDO) Read Modify Write Cycle



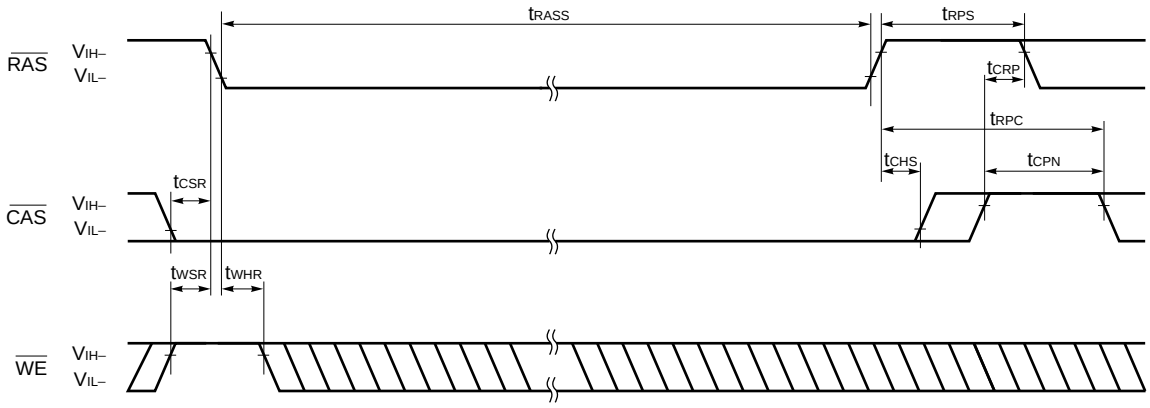
Remark In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive $\overline{CAS}$ cycles within the same $\overline{RAS}$ cycle.

Hyper Page Mode (EDO) Read and Write Cycle



Remark In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive $\overline{CAS}$ cycles within the same $\overline{RAS}$ cycle.

$\overline{CAS}$ Before $\overline{RAS}$ Self Refresh Cycle (Only for the μPD42S17405L)



Remark Address, $\overline{OE}$: Don't care I/O : Hi-Z

Cautions on Use of $\overline{CAS}$ Before $\overline{RAS}$ Self Refresh

$\overline{CAS}$ before $\overline{RAS}$ self refresh can be used independently when used in combination with distributed $\overline{CAS}$ before $\overline{RAS}$ long refresh; However, when used in combination with burst $\overline{CAS}$ before $\overline{RAS}$ long refresh or with long $\overline{RAS}$ only refresh (both distributed and burst), the following cautions must be observed.

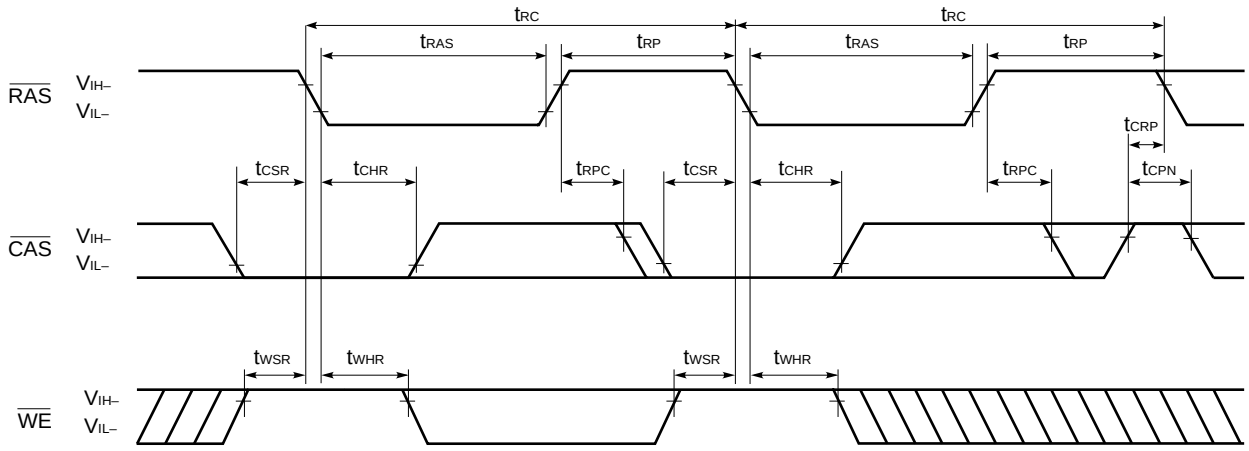
(1) Normal Combined Use of $\overline{CAS}$ Before $\overline{RAS}$ Self Refresh and Burst $\overline{CAS}$ Before $\overline{RAS}$ Long Refresh
When $\overline{CAS}$ before $\overline{RAS}$ self refresh and burst $\overline{CAS}$ before $\overline{RAS}$ long refresh are used in combination, please perform $\overline{CAS}$ before $\overline{RAS}$ refresh 2,048 times within a 32 ms interval just before and after setting $\overline{CAS}$ before $\overline{RAS}$ self refresh.

(2) Normal Combined Use of $\overline{CAS}$ Before $\overline{RAS}$ Self Refresh and Long $\overline{RAS}$ Only Refresh
When $\overline{CAS}$ before $\overline{RAS}$ self refresh and $\overline{RAS}$ only refresh are used in combination, please perform $\overline{RAS}$ only refresh 2,048 times within a 32 ms interval just before and after setting $\overline{CAS}$ before $\overline{RAS}$ self refresh.

(3) If $t_{RASS\ (MIN.)}$ is not satisfied at the beginning of $\overline{CAS}$ before $\overline{RAS}$ self refresh cycles (t_{RAS} < 100 μs), $\overline{CAS}$ before $\overline{RAS}$ refresh cycles will be executed one time.
If 10 μs < t_{RAS} < 100 μs, $\overline{RAS}$ precharge time for $\overline{CAS}$ before $\overline{RAS}$ self refresh (t_{RPS}) is applied.
And refresh cycles (2,048/128 ms) should be met.

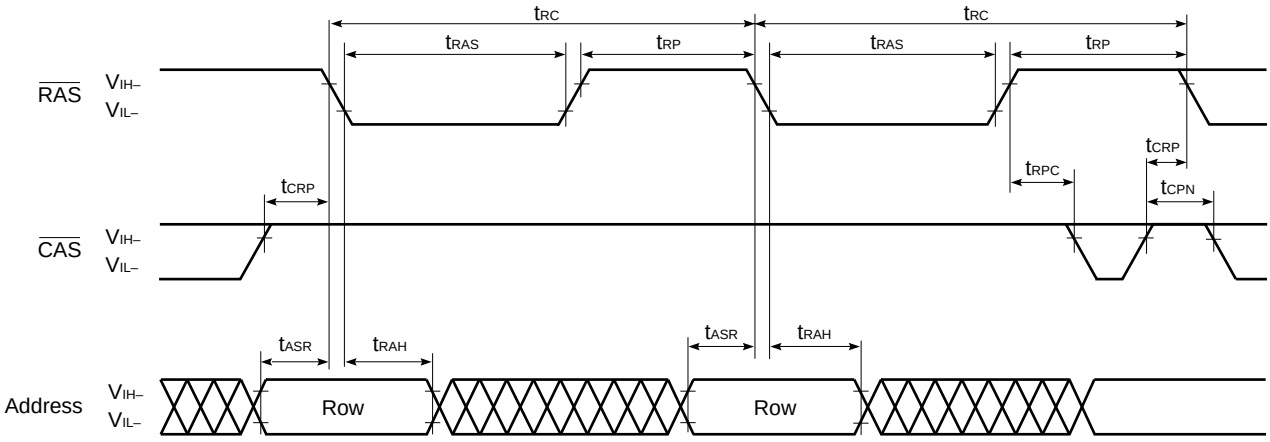
For details, please refer to **How to use DRAM** User's Manual.

$\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Cycle



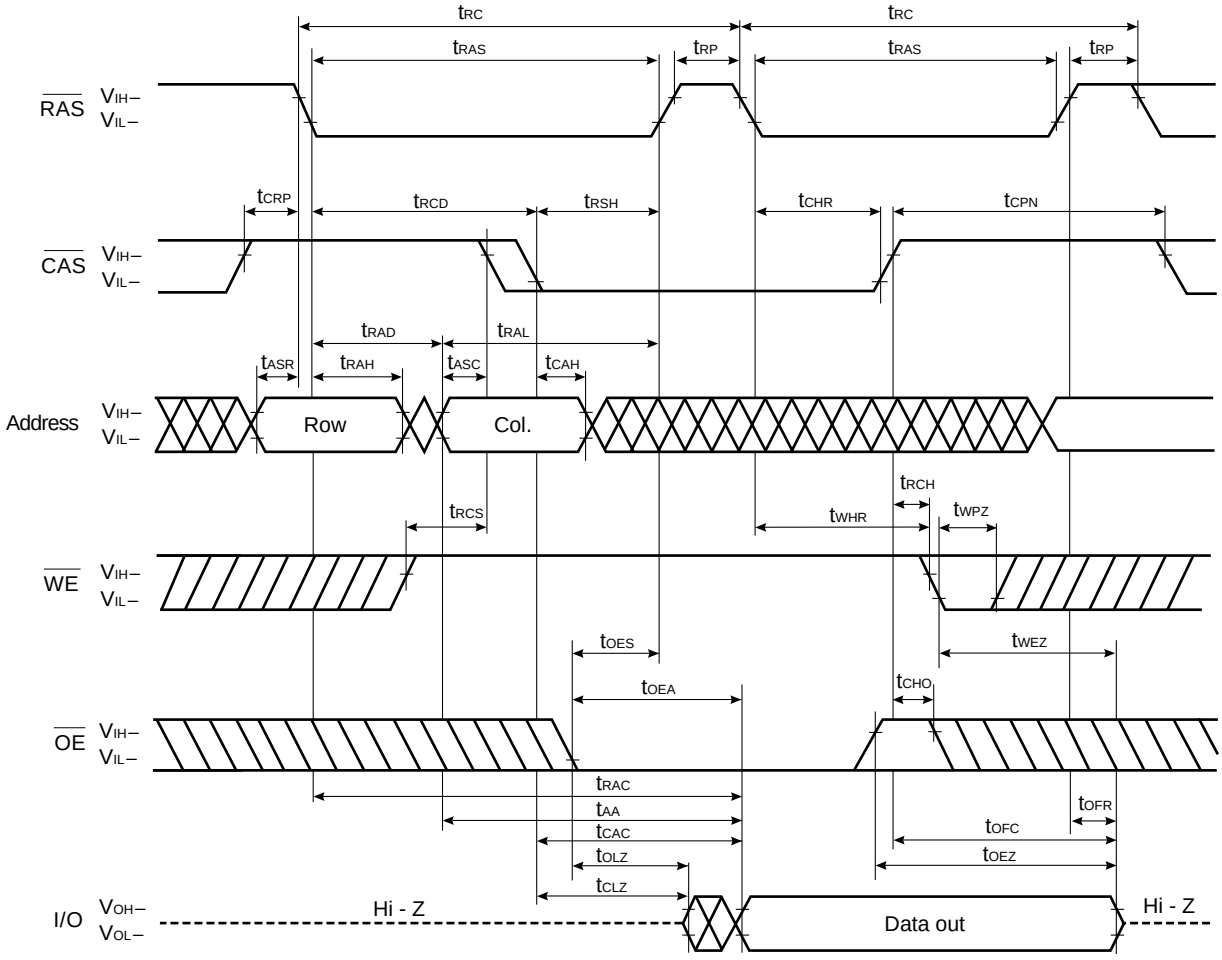
Remark Address, $\overline{\text{OE}}$: Don't care I/O: Hi-Z

$\overline{\text{RAS}}$ Only Refresh Cycle

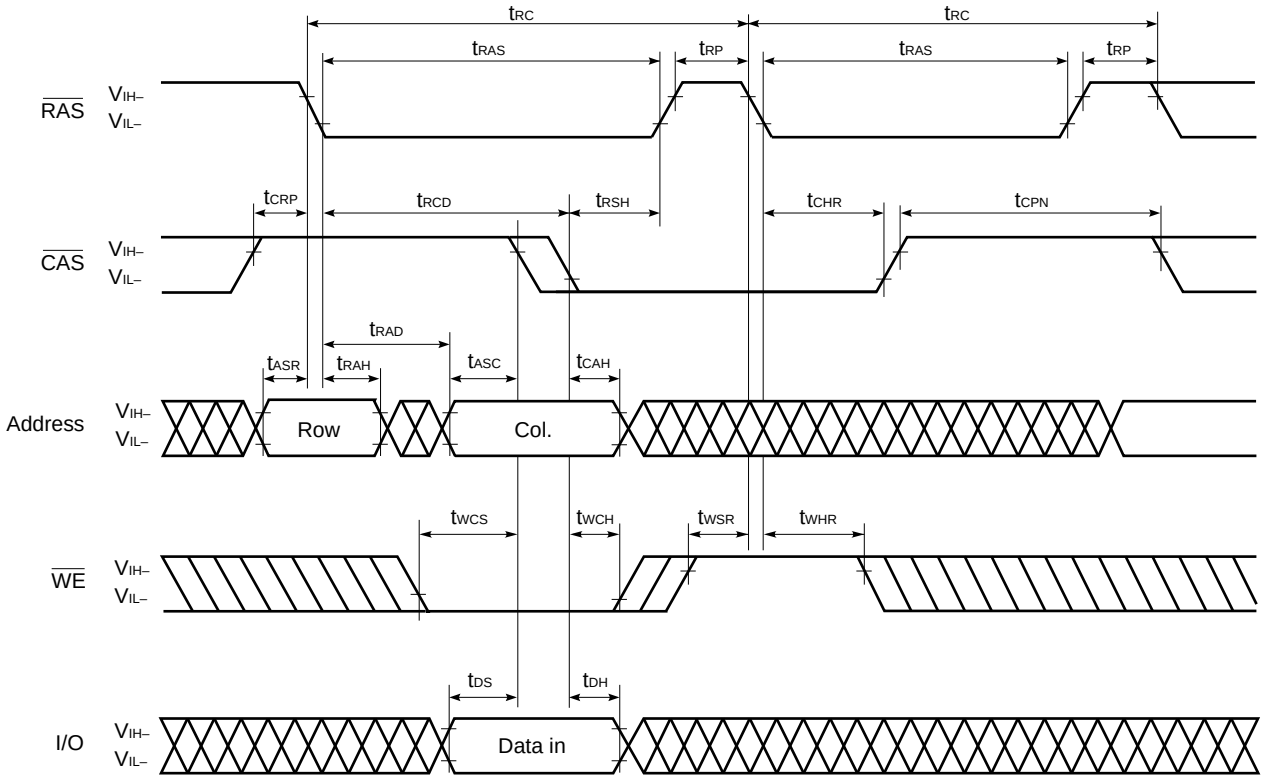


Remark $\overline{\text{WE}}$, $\overline{\text{OE}}$: Don't care I/O: Hi-Z

Hidden Refresh Cycle (Read)

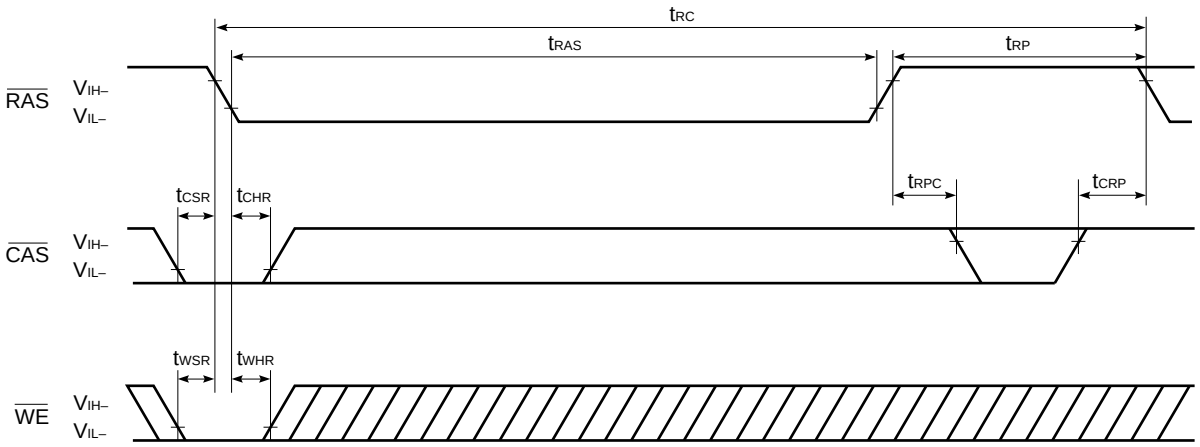


Hidden Refresh Cycle (Write)



Remark $\overline{OE}$: Don't care

Test Mode Set Cycle ($\overline{WE}$, $\overline{CAS}$ Before $\overline{RAS}$ Refresh Cycle)



Remark Address, $\overline{OE}$: Don't care I/O: Hi-Z

Test Mode

By using the test mode, the test time can be reduced. The reason for this is that, the memory emulates the × 16-bit organization during test mode. Don't care about the input levels of the $\overline{CAS}$ input A0, A1.

(1) Setting the mode

Executing the test mode cycle ($\overline{WE}$, $\overline{CAS}$ before $\overline{RAS}$ refresh cycle) sets the test mode.

(2) Write/read operation

When either a "0" or a "1" is written to the input pin in test mode, this data is written to 16 bits of memory cell.

Next, when the data is read from the output pin at the same address, the cell can be checked.

Output = "1": Normal write (all memory cells)
Output = "0": Abnormal write

(3) Refresh

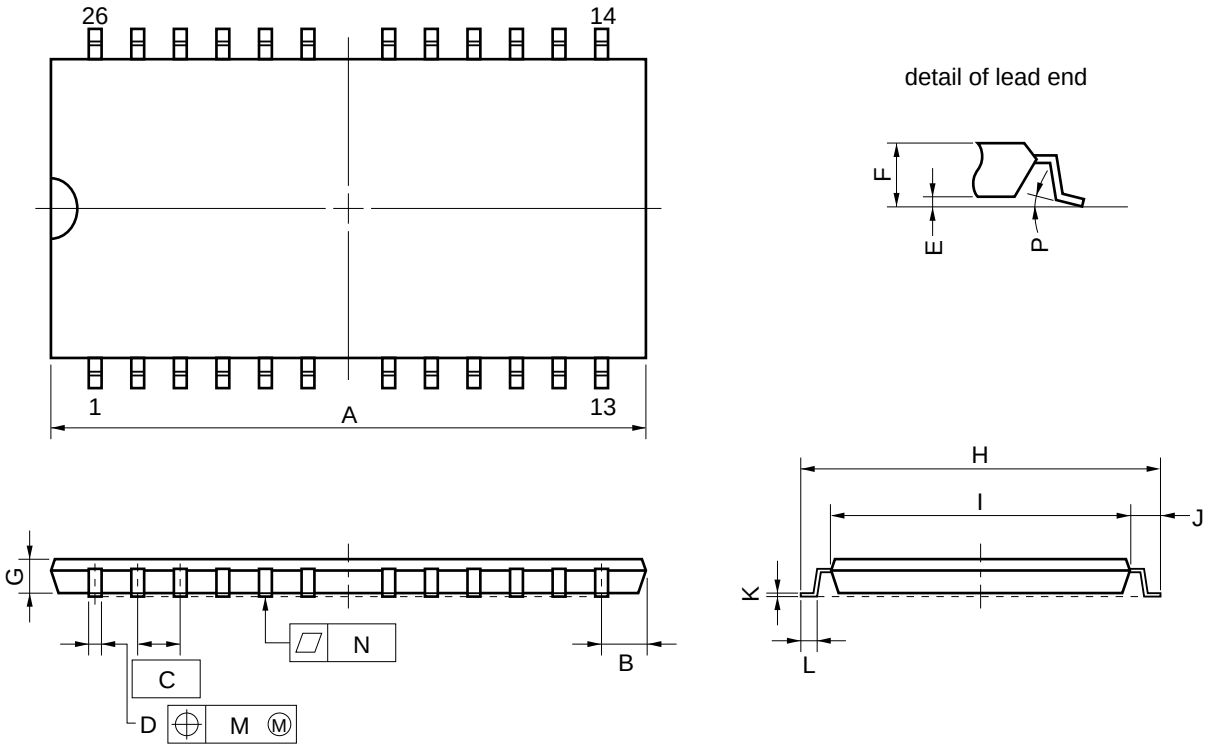
Refresh in the test mode must be performed with the $\overline{RAS}$ / $\overline{CAS}$ cycle or with the $\overline{WE}$, $\overline{CAS}$ before $\overline{RAS}$ refresh cycle. The $\overline{WE}$, $\overline{CAS}$ before $\overline{RAS}$ refresh cycle use the same counter as the $\overline{CAS}$ before $\overline{RAS}$ refresh's internal counter.

(4) Mode Cancellation

The test mode is cancelled by executing one cycle of $\overline{RAS}$ only refresh cycle or $\overline{CAS}$ before $\overline{RAS}$ refresh cycle.

Package Drawings

26PIN PLASTIC TSOP(II) (300 mil)



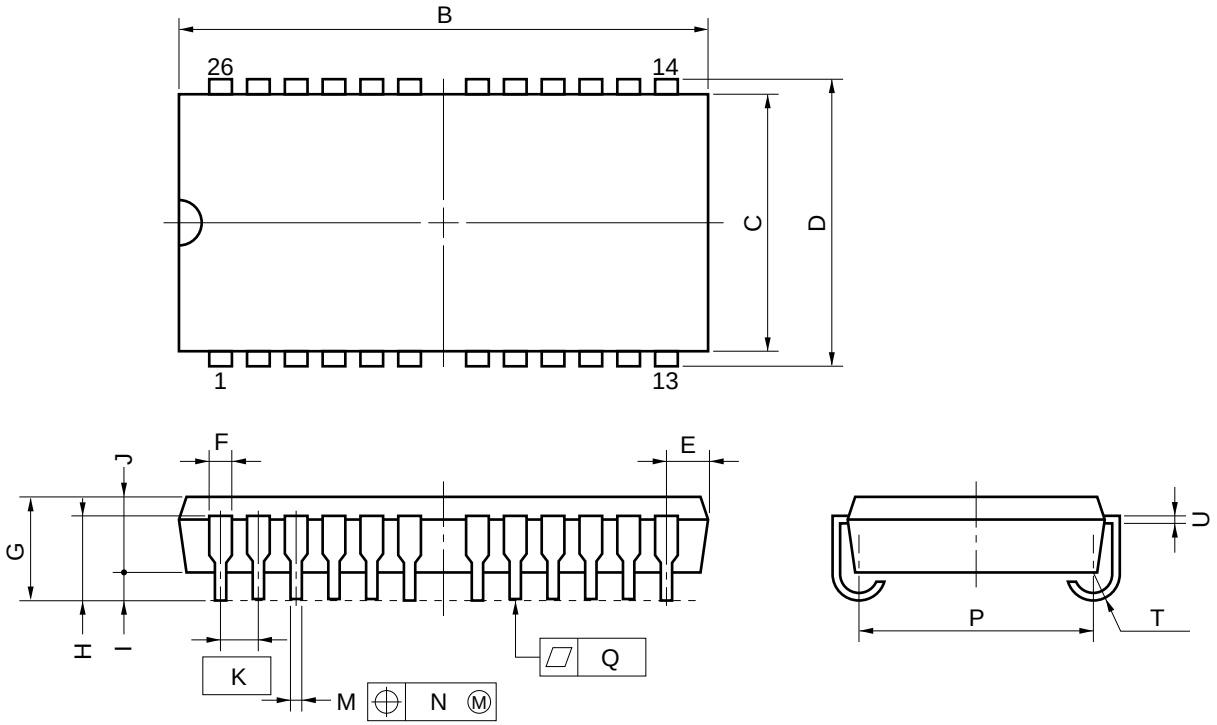
NOTE

Each lead centerline is located within 0.21 mm (0.009 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
A	17.36 MAX.	0.684 MAX.
B	1.06 MAX.	0.042 MAX.
C	1.27 (T.P.)	0.050 (T.P.)
D	$0.42^{+0.08}_{-0.07}$	0.017±0.003
E	0.1±0.05	0.004±0.002
F	1.2 MAX.	0.048 MAX.
G	0.97	0.038
H	9.22±0.2	0.363±0.008
I	7.62±0.1	0.300±0.004
J	0.8±0.2	$0.031^{+0.009}_{-0.008}$
K	$0.145^{+0.025}_{-0.015}$	0.006±0.001
L	0.5±0.1	$0.020^{+0.004}_{-0.005}$
M	0.21	0.009
N	0.10	0.004
P	$3^{\circ}{}^{+7^{\circ}}_{-3^{\circ}}$	$3^{\circ}{}^{+7^{\circ}}_{-3^{\circ}}$

S26G3-50-7JD1

26 PIN PLASTIC SOJ (300 mil)



NOTE

Each lead centerline is located within 0.12 mm (0.005 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
B	$17.3^{+0.20}_{-0.25}$	$0.681^{+0.008}_{-0.010}$
C	7.62	0.300
D	8.47±0.2	$0.333^{+0.009}_{-0.008}$
E	1.03±0.15	$0.041^{+0.006}_{-0.007}$
F	0.74	0.029
G	3.5±0.2	0.138±0.008
H	2.545±0.2	0.100±0.008
I	0.8 MIN.	0.031 MIN.
J	2.6	0.102
K	1.27 (T.P.)	0.050 (T.P.)
M	0.40±0.10	$0.016^{+0.004}_{-0.005}$
N	0.12	0.005
P	6.73±0.2	0.265±0.008
Q	0.10	0.004
T	R0.85	R0.033
U	$0.20^{+0.10}_{-0.05}$	$0.008^{+0.004}_{-0.002}$

S26LA-300A-1

★ Recommended Soldering Conditions

The following conditions (see tables below and next page) must be met for soldering conditions of the μPD42S17405L, 4217405L.

For more details, refer to our document "SEMICONDUCTOR DEVICE MOUNTING TECHNOLOGY MANUAL" (C10535E).

Please consult with our sales offices in case other soldering process is used, or in case the soldering is done under different conditions.

Types of Surface Mount Device

μPD42S17405LG3-7JD, 4217405LG3-7JD: 26-pin plastic TSOP (II) (300 mil)

Soldering process	Soldering conditions	Symbol
Infrared ray reflow	Peak temperature of package surface: 235 ˚C or lower, Reflow time: 30 seconds or less (210 ˚C or higher), Number of reflow processes: MAX. 3 Exposure limit: 7 days[Note] (10 hours pre-baking is required at 125 ˚C afterwards)	IR35-107-3
VPS	Peak temperature of package: 215 ˚C or lower, Reflow time: 40 seconds or less (200 ˚C or higher), Number of reflow processes: MAX. 3 Exposure limit: 7 days[Note] (10 hours pre-baking is required at 125 ˚C afterwards)	VP15-107-3
Partial heating method	Terminal temperature: 300 ˚C or lower, Time: 3 seconds or lower (Per side of the package).	———

Note Exposure limit before soldering after dry-pack package is opened.
Storage conditions: 25 ˚C and relative humidity at 65 % or less.

Caution Do not apply more than one soldering method at any one time, except for "Partial heating method".

μPD42S17405LLA, 4217405LLA: 26-pin plastic SOJ (300 mil)

Soldering process	Soldering conditions	Symbol
Infrared ray reflow	Peak temperature of package surface: 235 °C or lower, Reflow time: 30 seconds or less (210 °C or higher), Number of reflow processes: MAX. 3 Exposure limit: 7 days[Note] (20 hours pre-baking is required at 125 °C afterwards)	IR35-207-3
VPS	Peak temperature of package: 215 °C or lower, Reflow time: 40 seconds or less (200 °C or higher), Number of reflow processes: MAX. 3 Exposure limit: 7 days[Note] (20 hours pre-baking is required at 125 °C afterwards)	VP15-207-3
Partial heating method	Terminal temperature: 300 °C or lower, Time: 3 seconds or less (Per side of the package).	———

Note Exposure limit before soldering after dry-pack package is opened.
Storage conditions: 25 °C and relative humidity at 65 % or less.

Caution Do not apply more than one soldering method at any one time, except for "Partial heating method".

NOTES FOR CMOS DEVICES

① PRECAUTION AGAINST ESD FOR SEMICONDUCTORS

Note: Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

② HANDLING OF UNUSED INPUT PINS FOR CMOS

Note: No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS device behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to V_{DD} or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

③ STATUS BEFORE INITIALIZATION OF MOS DEVICES

Note: Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

[MEMO]

M4 96.5